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Application/Control No. 10/046,926	Applicant(s)/Patent under Reexamination TEIG ET AL.
Examiner	Art Unit
Vuthe Siek	2825

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		ORIGINAL		·	INTERNATIONAL CLASSIFICATION									
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	CROSS REFERENCES								,			,		
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(Assi	(Assistant Examiner) (Date) VUT					SIEK	<u>, </u>	6/29/06	Total Claims Allowed: 12					
// // >> PP					PINARY EXAMINER/ (Primary Examiner) (Date)					O.G.				
garin							60B,63							

	Claims renumbered in the same order as presented by applicant							☐ CPA			☐ T.D.			☐ R.1.47					
Final	Original		Final	Original		Final	Original		Final	Original	•	Final	Original		Final	Original		Final	Original
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	3			33			63			93			123			153			183
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2	7			37			67			97			127			157		<u> </u>	187
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